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## 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Va	Unit	
Symbol	Farameter	SOT-223	TO-92	Onit
V <sub>DS</sub>	Drain-source voltage	60	00	V
V <sub>GS</sub>	Gate-source voltage	±	30	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25 °C	0	.3	А
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> =100 °C	0.189		А
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	1.2		Α
P <sub>TOT</sub>	Total dissipation at T <sub>C</sub> = 25 °C	3.3	3	W
	Derating factor	0.026	0.024	W/°C
ESD	Human body model C=100 pF, R=1.5 $k\Omega$	800		V
dv/dt <sup>(2)</sup>	Peak diode recovery voltage slope	4.5		V/ns
TJ	Operating junction temperature	- 55 t	o 150	°C
T <sub>stg</sub>	Storage temperature	- 55 (	0 130	°C

<sup>1.</sup> Pulse width limited by safe operating area

Table 3. Thermal resistance

Symbol		Parameter	V	Unit	
Symbol	i di dinetei	SOT-223	TO-92		
R <sub>thj-a</sub>	R <sub>thj-amb</sub> Thermal resistance junction-ambient max		38 <sup>(1)</sup>	120	°C/W
R <sub>thj-lead</sub> Thermal resistance junction-lead max			40	°C/W	

<sup>1.</sup> When mounted on 1 inch<sup>2</sup> FR-4 board, 2 Oz Cu, t < 30 s.

Table 4. Avalanche data

Symbol	Parameter	Value	Unit
I <sub>AR</sub>	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{j \text{ max}}$ )	0.3	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	60	mJ

<sup>2.</sup>  $I_{SD} \le 0.3 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, V_{DD} = 80\%V_{(BR)DSS}$ 

### 2 Electrical characteristics

(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter Test conditions Min.		Тур.	Max.	Unit	
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	$V_{GS}$ = 0, $I_D$ = 1 mA	600			V
	Zero gate voltage drain current	V <sub>GS</sub> = 0, V <sub>DS</sub> =600 V			1	μΑ
I <sub>DSS</sub>		V <sub>GS</sub> = 0, V <sub>DS</sub> =600 V, T <sub>C</sub> = 125 °C			50	μА
I <sub>GSS</sub>	Gate body leakage current	$V_{DS} = 0, V_{GS} = \pm 20 \text{ V}$			±10	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 50 \mu A$	3	3.75	4.5	V
R <sub>DS(on)</sub> Static drain-source on- resistance		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.4 A		13	15	Ω

Table 6. Dynamic

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
g <sub>fs</sub> (1)	Forward transconductance	$V_{DS} = 15 \text{ V}, I_D = 0.4 \text{ A}$	-	0.5		S
C <sub>iss</sub>	Input capacitance		-	94		pF
C <sub>oss</sub>	Output capacitance	$V_{GS} = 0, V_{DS} = 25 \text{ V},$	i	17.6		pF
C <sub>rss</sub>	Reverse transfer capacitance	f=1 MHz	-	2.8		pF
Coss eq <sup>(2)</sup>	Equivalent output capacitance	$V_{GS} = 0$ , $V_{DS} = 0$ to 480 V	1	11		pF
Qg	Total gate charge	V <sub>DD</sub> =480 V, I <sub>D</sub> = 0.8 A	-	4.9	6.9	nC
Q <sub>gs</sub>	Gate-source charge	V <sub>GS</sub> =10 V	-	1		nC
Q <sub>gd</sub>	Gate-drain charge	(see Figure 19)	-	2.7		nC

<sup>1.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

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<sup>2.</sup>  $C_{oss\ eq.}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ 

Table 7. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time		-	5.5	-	ns
t <sub>r</sub>	Rise time	$V_{DD} = 300 \text{ V}, I_D = 0.4 \text{ A},$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	5	-	ns
t <sub>d(off)</sub>	Turn-off delay time	(see Figure 18)	-	13	-	ns
t <sub>f</sub>	Fall time	,	-	28	-	ns

Table 8. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current		-		0.8	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		2.4	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	$V_{GS}=0$ , $I_{SD}=0.8$ A	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 0.8 A,	-	135		ns
Q <sub>rr</sub>	Reverse recovery charge	di/dt = 100 A/μs,	-	216		nC
I <sub>RRM</sub>	Reverse recovery current	V <sub>DD</sub> = 20 V	-	3.2		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 0.8 A,	-	140		ns
Q <sub>rr</sub>	Reverse recovery charge	di/dt = 100 A/µs,	-	224		nC
I <sub>RRM</sub>	Reverse recovery current	V <sub>DD</sub> = 20V, Tj = 150 °C	-	3.2		Α

<sup>1.</sup> Pulse width limited by safe operating area.

Table 9. Gate-source Zener diode

Symbol	Parameter	Test conditions	Min	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1$ mA, $I_{D}=0$	30	-	-	V

The built-in back-to-back Zener diodes have specifically been designed to enhance the device's ESD capability. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.



<sup>2.</sup> Pulsed: pulse duration=300µs, duty cycle 1.5%

### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for SOT-223

Figure 3. Thermal impedance for SOT-223

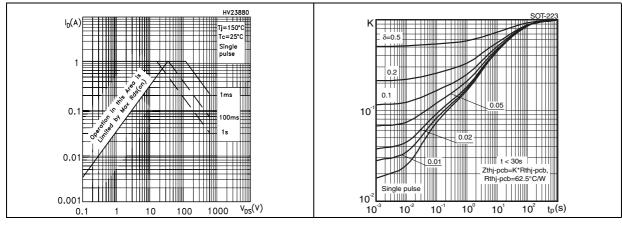


Figure 4. Safe operating area for TO-92

Figure 5. Thermal impedance for TO-92

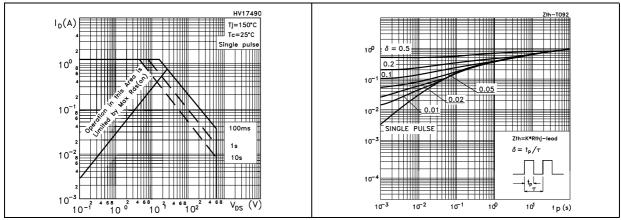


Figure 6. Output characteristics

Figure 7. Transfer characteristics

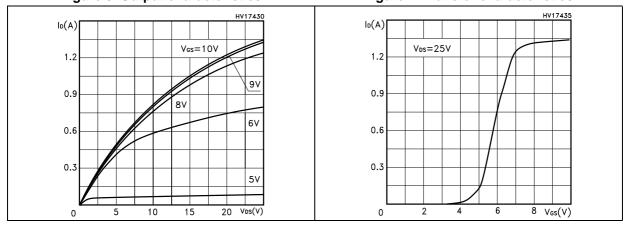


Figure 8. Transconductance

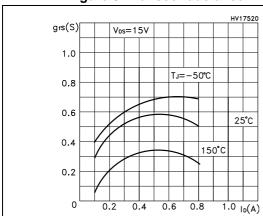


Figure 9. Static drain-source on-resistance

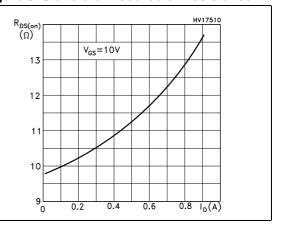


Figure 10. Gate charge vs gate-source voltage

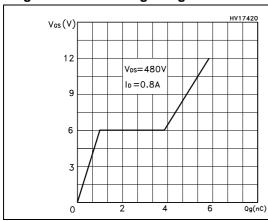


Figure 11. Capacitance variations

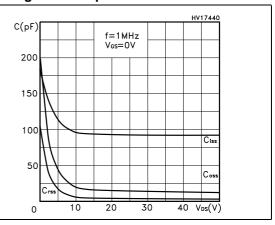


Figure 12. Normalized gate threshold voltage vs temperature

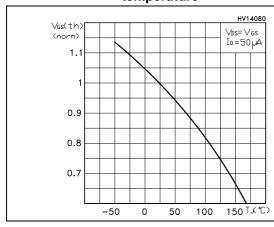


Figure 13. Normalized on-resistance vs temperature

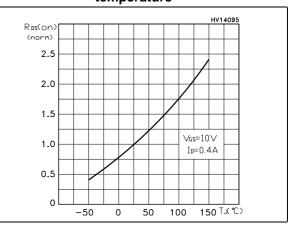
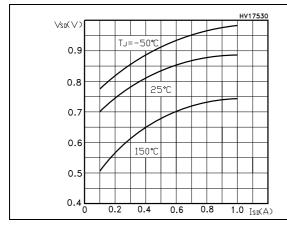


Figure 14. Source-drain diode forward characteristics

Figure 15. Normalized  $V_{BR(DSS)}$  vs temperature



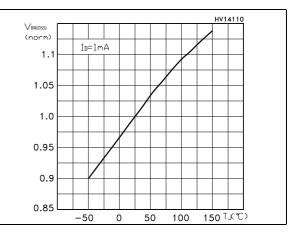
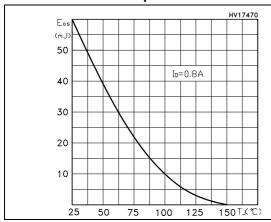
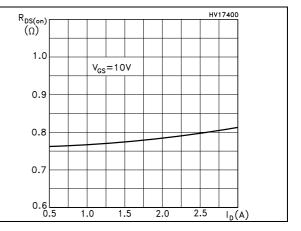


Figure 16. Maximum avalanche energy vs temperature

Figure 17. Max Id current vs Tc





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### 3 Test circuits

Figure 18. Switching times test circuit for resistive load

Figure 19. Gate charge test circuit

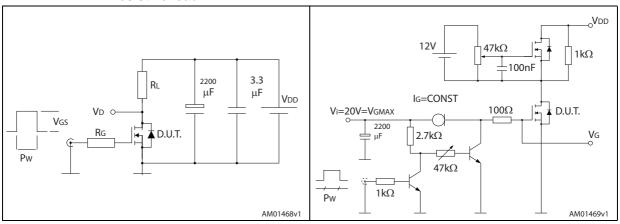


Figure 20. Test circuit for inductive load switching and diode recovery times

Figure 21. Unclamped inductive load test circuit

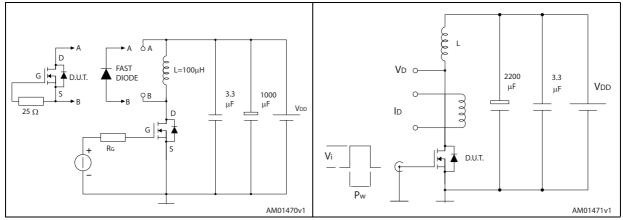
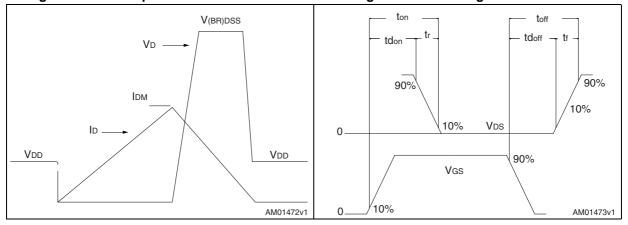


Figure 22. Unclamped inductive waveform

Figure 23. Switching time waveform





# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.

D B1 1 2 3 0046067\_N

Figure 24. SOT-223 mechanical data drawing

Table 10. SOT-223 mechanical data

Dim		mm				
Dim.	Min.	Тур.	Max.			
А			1.80			
A1	0.02		0.10			
В	0.60	0.70	0.85			
B1	2.9	3.0	3.15			
С	0.24	0.26	0.35			
D	6.30	6.50	6.70			
е		2.30	6.70			
e1		4.60				
E	3.30	3.50	3.70			
Н	6.70	7.0	7.30			
V			10°			

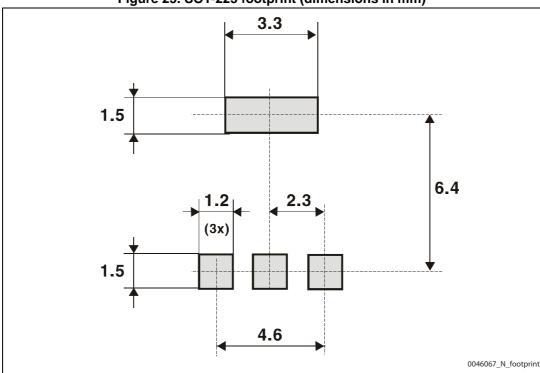


Figure 25. SOT-223 footprint (dimensions in mm)

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#### 4.1 **SOT-223, STN1NK60Z**

#### TO-92 ammopack, STQ1NK60ZR-AP 4.2

Figure 26. TO-92 ammopack mechanical data drawing delta H 0050910S\_Rev\_U

Table 11. TO-92 ammopack mechanical data

Dim		mm	
Dim.	Min.	Тур.	Max.
A1			4.80
Т			3.80
T1			1.60
T2			2.30
d	0.45	0.47	0.48
P0	12.50	12.70	12.90
P2	5.65	6.35	7.05
F1, F2	2.40	2.50	2.94
F3	4.98	5.08	5.48
delta H	-2.00		2.00
W	17.50	18.00	19.00
W0	5.5	6.00	6.5
W1	8.50	9.00	9.25
W2			0.50
Н		18.50	21
H3	0.5	1	2
H0	15.50	16.00	18.8
H1		25.0	27.0
D0	3.80	4.00	4.20
t			0.90
L			11.00
I1	3.00		
delta P	-1.00		1.00

## 5 Packaging mechanical data

TOP COVER TAPE

P2

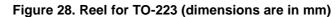
P0

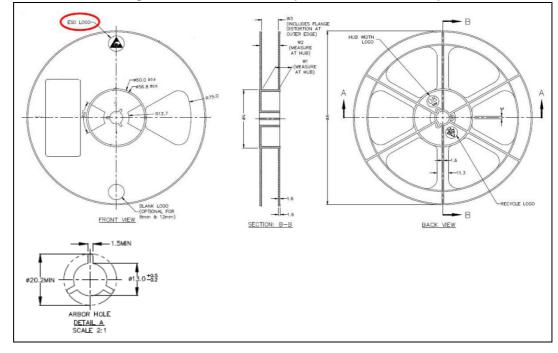
B0

P1

\*Cumulative tolerance of 10 sprocket holes is ±0.20 mm

Figure 27. Tape for SOT-223 (dimensions are in mm)







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Table 12. SOT-223 tape and reel mechanical data

Таре					Reel	
Dim.		mm				nm
Dim.	Min.	Тур.	Max.	Dim.	Min.	Max.
A0	6.75	6.85	6.95	А		180
В0	7.30	7.40	7.50	N	60	
K0	1.80	1.90	2.00	W1		12.4
F	5.40	5.50	5.60	W2		18.4
E	1.65	1.75	1.85	W3	11.9	15.4
W	11.7	12	12.3			
P2	1.90	2	2.10	Base qu	antity pcs	1000
P0	3.90	4	4.10	Bulk qua	antity pcs	1000
P1	7.90	8	8.10			
Т	0.25	0.30	0.35			
Dφ	1.50	1.55	1.60			
D1ф	1.50	1.60	1.70			

# 6 Revision history

Table 13. Revision history

Date	Revision	Changes
19-Mar-2003	3	First electronic version
15-May-2003	4	Removed DPAK
09-Jun-2003	5	Final datasheet
17-Nov-2004	6	Inserted SOT-223
15-Feb-2005	7	Modified Figure 4.
07-Sep-2005	8	Inserted ecopack indication
22-Feb-2006	9	The document has been reformatted
01-Jun-2007	10	Order code table on first page has been updated
19-Jul-2007	11	Table 1: Device summary has been updated
05-Jan-2011	12	Corrected Figure 2: Safe operating area for SOT-223 and Figure 3: Thermal impedance for SOT-223
05-Jun-2014	13	<ul> <li>Updated title.</li> <li>Updated derating factor in <i>Table 2: Absolute maximum ratings</i>.</li> <li>Updated <i>Section 4: Package mechanical data</i>.</li> <li>Minor text changes.</li> </ul>
04-Jul-2014	14	- Updated Section 3: Test circuits.



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